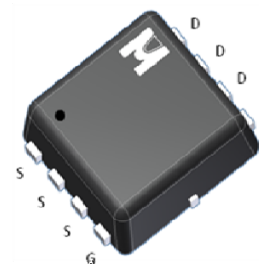
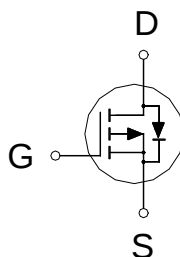


P-Channel Logic Level Enhancement Mode Field Effect Transistor

Product Summary:

BV_{DSS}	-20V
$R_{DS(on)} (MAX.)$	6.3m Ω
I_D	-46A



UIS, Rg 100% Tested

Pb-Free Lead Plating & Halogen Free

ABSOLUTE MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNIT
Gate-Source Voltage		V_{GS}	± 12	V
Continuous Drain Current	$T_C = 25^\circ\text{C}$	I_D	-46	A
	$T_A = 25^\circ\text{C}$		-16	
	$T_C = 100^\circ\text{C}$		-29	
Pulsed Drain Current ¹		I_{DM}	-180	
Avalanche Current		I_{AS}	-48	
Avalanche Energy	$L = 0.1\text{mH}$, $I_{AS} = -48\text{A}$, $R_G = 25\Omega$	E_{AS}	115	mJ
Repetitive Avalanche Energy ²	$L = 0.05\text{mH}$	E_{AR}	57	
Power Dissipation	$T_C = 25^\circ\text{C}$	P_D	21	W
	$T_C = 100^\circ\text{C}$		8.3	
Power Dissipation	$T_A = 25^\circ\text{C}$	P_D	2.5	W
	$T_A = 100^\circ\text{C}$		1	
Operating Junction & Storage Temperature Range		$T_{j, T_{stg}}$	-55 to 150	$^\circ\text{C}$

100% UIS testing in condition of $V_D = -15\text{V}$, $L = 0.1\text{mH}$, $V_G = -5\text{V}$, $I_L = -20\text{A}$, Rated $V_{DS} = -20\text{V}$ P-CH

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNIT
Junction-to-Case	$R_{\theta JC}$		6	$^\circ\text{C} / \text{W}$
Junction-to-Ambient ³	$R_{\theta JA}$		50	

¹Pulse width limited by maximum junction temperature.

²Duty cycle $\leq 1\%$

³50°C / W when mounted on a 1 in² pad of 2 oz copper.

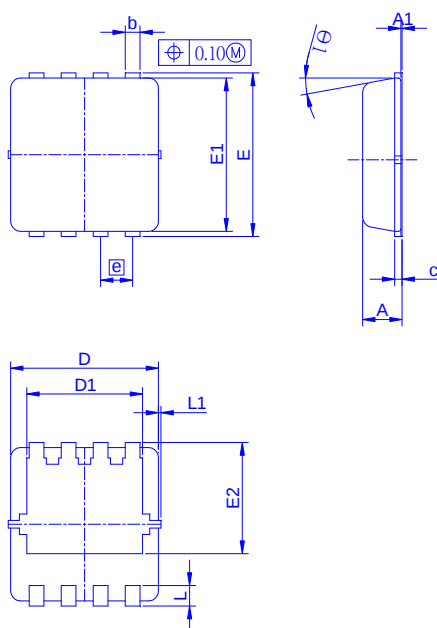
ELECTRICAL CHARACTERISTICS (T_J = 25 °C, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	V _{(BR)DSS}	V _{GS} = 0V, I _D = -250μA	-20			V
Gate Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = -250μA	-0.4	-0.6	-1.2	
Gate-Body Leakage	I _{GSS}	V _{DS} = 0V, V _{GS} = ±12V			±100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = -16V, V _{GS} = 0V			-1	μA
		V _{DS} = -12V, V _{GS} = 0V, T _J = 125 °C			-10	
On-State Drain Current ¹	I _{D(ON)}	V _{DS} = -5V, V _{GS} = -4.5V	-46			A
Drain-Source On-State Resistance ¹	R _{DS(ON)}	V _{GS} = -4.5V, I _D = -20A		5.6	6.3	mΩ
		V _{GS} = -2.5V, I _D = -20A		6.7	7.5	
		V _{GS} = -1.8V, I _D = -20A		8.4	9.5	
Forward Transconductance ¹	g _{fs}	V _{DS} = -5V, I _D = -20A		52		S
DYNAMIC						
Input Capacitance	C _{iss}	V _{GS} = 0V, V _{DS} = -10V, f = 1MHz		6945		pF
Output Capacitance	C _{oss}			605		
Reverse Transfer Capacitance	C _{rss}			515		
Gate Resistance	R _g	V _{GS} = 15mV, V _{DS} = 0V, f = 1MHz		3.3		Ω
Total Gate Charge ^{1,2}	Q _g	V _{DS} = -10V, V _{GS} = -4.5V, I _D = -20A		49		nC
Gate-Source Charge ^{1,2}	Q _{gs}			10		
Gate-Drain Charge ^{1,2}	Q _{gd}			7.6		
Turn-On Delay Time ^{1,2}	t _{d(on)}	V _{DS} = -10V, I _D = -1A, V _{GS} = -4.5V, R _{GS} = 6Ω		20		nS
Rise Time ^{1,2}	t _r			50		
Turn-Off Delay Time ^{1,2}	t _{d(off)}			250		
Fall Time ^{1,2}	t _f			120		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (T _C = 25 °C)						
Continuous Current	I _S				-46	A
Pulsed Current ³	I _{SM}				-180	
Forward Voltage ¹	V _{SD}	I _F = -20A, V _{GS} = 0V			-1.2	V
Reverse Recovery Time	t _{rr}	I _F = -20A, dI _F /dt = 100A / μS		75		nS
Reverse Recovery Charge	Q _{rr}			480		nC

¹Pulse test : Pulse Width ≤ 300 μsec, Duty Cycle ≤ 2%.

³Pulse width limited by maximum junction temperature.

Device Name: EMF04P02V for EDFN 3 x 3



Dimension	A	A1	b	c	D	D1	E	E1	E2	e	L	L1	Θ1
Min.	0.65	0	0.20	0.10	2.90	2.15	3.10	2.90	1.53	0.55	0.25	-	0°
Typ.	0.75	-	0.30	0.15	3.00	2.45	3.20	3.00	1.97	0.65	0.40	0.075	10°
Max.	0.90	0.05	0.40	0.25	3.30	2.74	3.50	3.30	2.59	0.75	0.60	0.150	14°



TYPICAL CHARACTERISTICS

